

09915854\_CLS  
Most Frequently Occurring Classifications of Patents Returned  
From A Search of 09915854 on November 20, 2003

Original Classifications

4 714/724  
3 250/310  
3 714/719  
3 714/733  
2 714/731  
2 714/736  
2 714/738

Cross-Reference Classifications

3 714/724  
3 714/736  
2 324/73.1  
2 326/16  
2 365/201  
2 714/733  
2 714/734  
2 714/735  
2 714/738

Combined Classifications

7 714/724  
5 714/733  
5 714/736  
4 250/310  
4 714/738  
3 324/73.1  
3 365/201  
3 714/719  
3 714/734  
2 250/492.2  
2 326/16  
2 714/726  
2 714/731  
2 714/735  
2 714/739  
2 714/744  
2 716/17  
2 716/4

09915854\_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09915854 on November 20, 2003

- 7 714/724 (4 OR, 3 XR)
  - Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY
  - 714/699 PULSE OR DATA ERROR HANDLING
  - 714/724 .Digital logic testing
  
- 5 714/733 (3 OR, 2 XR)
  - Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY
  - 714/699 PULSE OR DATA ERROR HANDLING
  - 714/724 .Digital logic testing
  - 714/733 ..Built-in testing circuit (BILBO)
  
- 5 714/736 (2 OR, 3 XR)
  - Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY
  - 714/699 PULSE OR DATA ERROR HANDLING
  - 714/724 .Digital logic testing
  - 714/736 ..Device response compared to expected  
fault-free response
  
- 4 250/310 (3 OR, 1 XR)
  - Class 250 : RADIANT ENERGY
  - 250/306 INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED  
PARTICLES
  - 250/310 .Electron probe type
  
- 4 714/738 (2 OR, 2 XR)
  - Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY
  - 714/699 PULSE OR DATA ERROR HANDLING
  - 714/724 .Digital logic testing
  - 714/738 ..Including test pattern generator
  
- 3 324/73.1 (1 OR, 2 XR)
  - Class 324 : ELECTRICITY: MEASURING AND TESTING
  - 324/73.1 PLURAL, AUTOMATICALLY SEQUENTIAL TESTS
  
- 3 365/201 (1 OR, 2 XR)
  - Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
  - 365/189.01 READ/WRITE CIRCUIT
  - 365/201 .Testing

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- 3 714/719 (3 OR, 0 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/718 .Memory testing  
 714/719 ..Read-in with read-out and compare
- 3 714/734 (1 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing  
 714/734 ..Structural (in-circuit test)
- 2 250/492.2 (1 OR, 1 XR)  
 Class 250 : RADIANT ENERGY  
 250/492.1 IRRADIATION OF OBJECTS OR MATERIAL  
 250/492.2 .Irradiation of semiconductor devices
- 2 326/16 (0 OR, 2 XR)  
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY  
 326/16 WITH TEST FACILITATING FEATURE
- 2 714/726 (1 OR, 1 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing  
 714/726 ..Scan path testing (e.g., level sensitive scan  
 design (LSSD))
- 2 714/731 (2 OR, 0 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing  
 714/726 ..Scan path testing (e.g., level sensitive scan  
 design (LSSD))  
 714/731 ...Clock or synchronization
- 2 714/735 (0 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing  
 714/735 ..Device response compared to input pattern

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- 2 714/739 (1 OR, 1 XR)
  - Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY
  - 714/699 PULSE OR DATA ERROR HANDLING
  - 714/724 .Digital logic testing
  - 714/738 ..Including test pattern generator
  - 714/739 ...Random pattern generation (includes  
pseudorandom pattern)
  
- 2 714/744 (1 OR, 1 XR)
  - Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY
  - 714/699 PULSE OR DATA ERROR HANDLING
  - 714/724 .Digital logic testing
  - 714/738 ..Including test pattern generator
  - 714/744 ...Clock or synchronization
  
- 2 716/17 (1 OR, 1 XR)
  - Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF  
CIRCUIT OR SEMICONDUCTOR MASK
  - 716/1 CIRCUIT DESIGN
  - 716/17 .Programmable integrated circuit (e.g., basic  
cell, standard cell, macrocell)
  
- 2 716/4 (1 OR, 1 XR)
  - Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF  
CIRCUIT OR SEMICONDUCTOR MASK
  - 716/1 CIRCUIT DESIGN
  - 716/4 .Testing or evaluating

09915854 LIST

PLUS Search Results for S/N 09915854, Searched November 20, 2003

5499249  
4423509  
4967151  
4571679  
4853928  
4875209  
5253181  
5323400  
5627841  
5850512  
6000040  
6130428  
6167542  
6211517  
6211517  
5436912  
4414669  
4625310  
4811343  
4951220  
5278841  
5357471  
5404359  
5600658  
4308616  
4896322  
5550839  
5748638  
5944846  
4267463  
4293950  
4371952  
4387304  
4546473  
4575718  
4594704  
4764926  
4772845  
4858156  
5177318  
5297151  
5377203  
5550844  
5602856  
5744946  
5844916

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5898705

5930814

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